Magneto Optical and Microstructural Investigation of Grain Boundaries in Large Grain High Purity Niobium for Superconducting RF Cavities

P. J. Lee, A. A. Polyanskii (Magneto Optical Imaging), Z. H. Sung (TEM, EELS), A. Gurevich, D. C. Larbalestier

Applied Superconductivity Center, National High Magnetic Field Laboratory - FSU

C. Antoine, P. C. Bauer*, C. Boffo, and H. C. Edwards

Fermilab

*now at ITER







Possible Sources of Cavity Degradation

Surface Topology/Debris

Microstructure

Chemistry





The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

Large Grain **CBMM** Slice from JeffersonLab as Test-bed

Allows testing of individual microstructural features through-processing



Magneto Optical Imaging: Allows Direct Imaging of B_z in Plane Above Sample

Double Faraday effect occurs in reflective mode using Bidoped YIG indicator film with in-plane magnetization



Sample Selection



The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

Previously (SRF'05 – Physica C)







Depth Map, 5 µm Range

The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

- Examination of 2 bi-crystals and 2 tri-crystals showed premature flux penetration at only one grain boundary in one sample (perpendicular magnetic field).
- Flux penetrated grain boundary was parallel to external magnetic field.
- Topology did not appear to be a factor in this case (the nonpenetrated GBs had larger surface steps than the penetrated GB.

Experiment 1: Vary GB Angle to Surface





- Take sample with grain boundary at 35° to surface – that did not show flux penetration at GB in earlier MO.
- Rotate and re-slice sample so that the GB is now perpendicular to the top surface.

Magnetic flux now penetrates (magnetic field parallel to plane of GB).







But note: asymmetric penetration.

1 mm





The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

Thickness of sample is 1.89 mm



Experiment 2: Grain Boundary Orientation Sensitivity

What happens when the GB is not planar but twists through the sample?

Does this make the penetration asymmetric?

Test: slice the specimen once more to reduce thickness and top-to-bottom grain boundary displacement.



Sample thickness reduced to 0.3 mm





H=32 mT

H=40 mT





T=6 K

Now flux penetrates the GB from both sides -GB acts as weak link in both ZFC and FC states.

The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

But this sample is rough!

Surface has considerable roughness from cutting and a groove (a) that crosses the GB.





H=32 mT penetration superimposed on surface



The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

Conclusions from Experiment 2





Explanation for asymmetric flux penetration and the absence of MO contrast in FC in Expt. 1:

- High sensitivity to angle between GB and direction to externally applied field.
- Study of flux penetration along GB#2 in thin samples, when GB perpendicular to surface, shows weak link in both FC and ZFC.

Microstructure of the Grain Boundaries

- 1. Crystallographic disorientation measured using OIM in FESEM.
 - Penetration GBs had angular disorientations of 17.8° (SRF'05 perpendicular) and 32.7° (rotated sample this presentation)

GB#1 (normalto-surface) disorientation angle between grains ≈17.8° Orientation Imaging Microscopy (OIM): by D. Abraimov



GB#2 (originally 35° to surface) disorientation angle between grains ≈32.7° Orientation Imaging Microscopy (OIM): by D. Abraimov



The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

2. Microstructure by TEM GB1 (SRF'05 "weak" GB): TEM

Sample A: **Ground to ~10 µm thick then finish with BCP**: Dense dislocation networks remain from grinding. Sample B: Mechanical polishing stopped at ~20 µm. Then finish with BCP.



The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

BCP Can Produce Very Good TEM Foils



Light Microscope Overview



There is always some preferential BCP removal at GBs

The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

Surface Cold Work and Removal





- With only <5 µm removed by BCP there remains a dense dislocation array left by the grinding action of the polishing grit.
 - For the diamond-saw slices and mechanically polished surfaces of GB#2 in this presentation there will also have been a high density of dislocations, again to at least 5 µm in depth.



BCP can produce zero-step and minimal groove topology.

- In order to be able to produce an electron transparent TEM foil of the GB there must be little of no step or groove created at the GB.
 - Careful mechanical polishing followed by <10µm surface removal by BCP creates this condition here.

Polishing Recipe used for TEM sample in previous slide:

- I. Flatten the sample surface with 400 grit SiC paper
 Decrease the sample thickness with 600 grit SiC paper (14 µm), removing ~ 500 µm from each surface.
 - 3. Polish with 800 grit SiC paper (10 µm)
 - 4. Final Sandpaper grit is 1200 (5 μm)
 - 5. Use very low-force "Mini-Met" polisher with Alumina powders
 - (1 µm followed by 0.3 µm)

` The final step takes about 1 and half hour to remove all of scratches.



Note: Note: All SiC-paper steps performed *dry* – *as this reduces embedding of SiC into sample surface.*

Single Crystal Niobium Technology Workshop

CBMM. Araxá. Brazil. Oct. 30 – Nov. 1. 200

Grain Boundary Chemistry: Electron Energy Loss Spectroscopy in TEM

Successful GB TEM foils allow us to perform µ-chemical comparisons between the GB region and the Grain.



CBMM, Araxá, Brazil, Oct. 30 – Nov. 1, 2006

The National High Magnetic Field Laboratory - FSU

Summary of Multiple EELS Analyses

- Oxygen-K peak detectable in about 80% of in-grain regions (50-20 µm away from GB).
- Oxygen peak (K shell) not clearly visible in 100 nm diameter grain boundary analysis regions.
- Note: All surfaces will have some Nb oxide – so that level of oxygen is not being detected in these



traces.





Ar Ion Milling and FIB'ing Can Introduce Defects





Low angle Ar ion milling introduced dislocation & point defects (TEM Image left: Ar+ 2.5 kV, 5 mA,8° tilt, 10 min

Focused Ion Beam: produced very good foils for EELS but evidence for point defect/ion embedding damage.



The Applied Superconductivity Center The National High Magnetic Field Laboratory - FSU

Summary





- However, that weakness is only revealed when the grain boundary is close to parallel with the applied magnetic field.
- For randomly oriented sheet in an RF cavity, the larger the grains the greater the distance between these weak GB locations but the greater the length of weak GB at that location.
- Using TEM preparation techniques followed by BCP perfectly flat sample surfaces.
 - EELS consistently shows oxygen in grains away from GB *but* within 50 nm of GB the oxygen signal falls below detectable levels.

Acknowledgments

- Very large grain Nb slice provided to Applied Superconductivity Center by Peter Kneisel at the Thomas Jefferson National Accelerator Facility.
- OIM was performed by Dmytro Abraimov.
- Support for this work at the UW-ASC was through the DOE-LCRD under grant DE-FG02-05ER41392.

